

High precision solutions for cleanliness analysis



CLEMEX PSFILTER

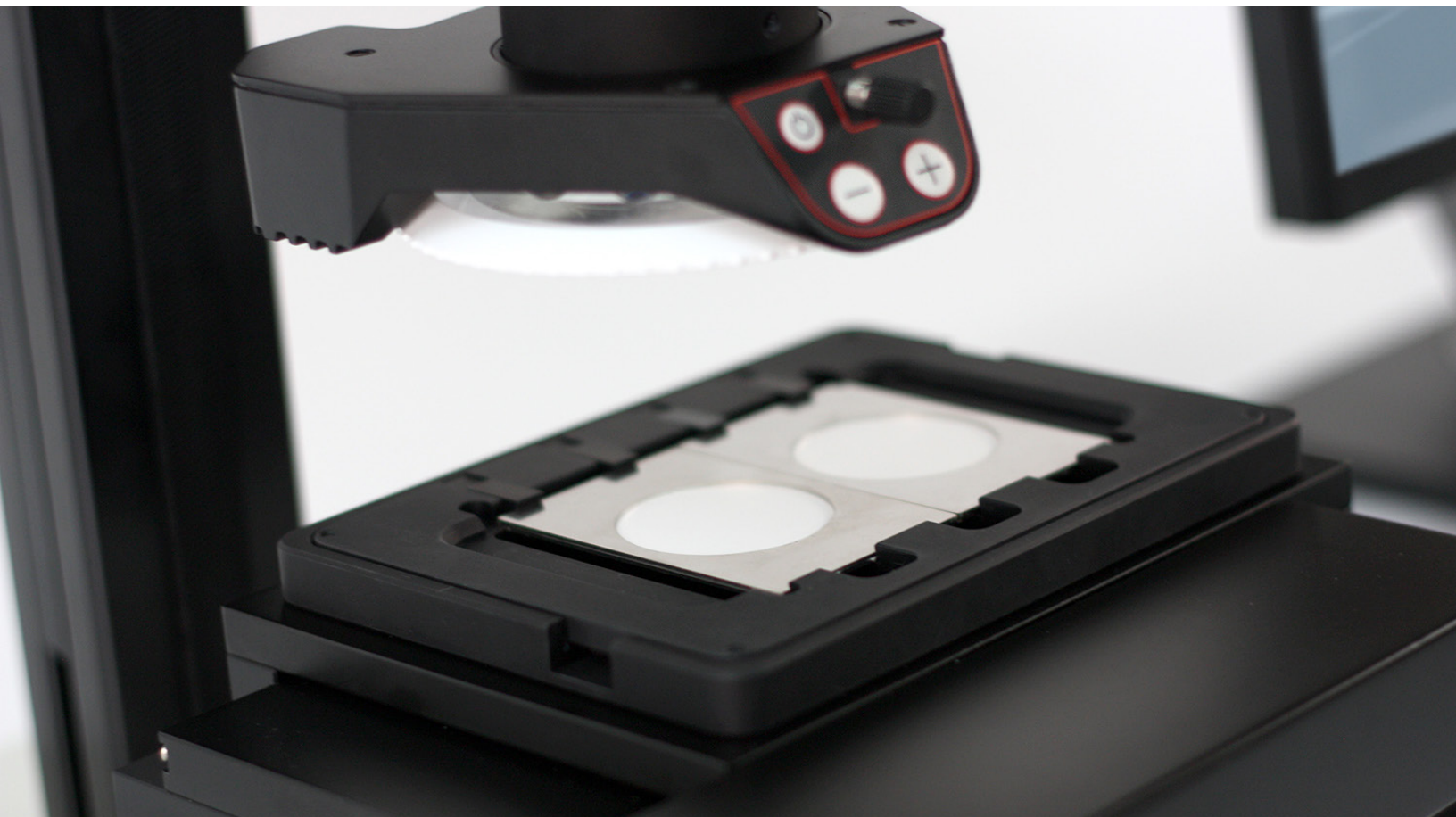
Accurate measurement of particulates as small as 0.5 microns

Installed and ready to analyze

Clemex PSFilter turnkey systems come with custom installation, calibration and after-sales service so you can get started quicker.

Particulate matter on medical devices

Automatic analysis of contamination levels according to USP 788 on membrane filters. For devices such as catheters, syringes and implants.



Understanding your challenges

Characterizing cleanliness

With Clemex PSFilter you gain a complete understanding of the sample material by generating statistically significant data, by using image analysis, and contrary to Laser Particulate Counting (LPC), the analyses are completely reproducible.

Conform to international standards

Clemex PSFilter allows to choose from pre-programmed international standards such as IESTSTD-CC1246D, ISO 16232, ISO 4406-4407, or USP 788. It also offers the option of customizing its properties so that in-house standards can be applied.

View the entire sample

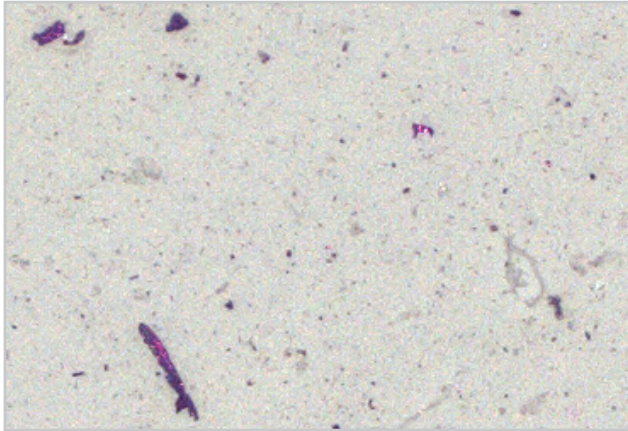
Clemex PSFilter accepts different types of samples: membrane filters, wafers, tape lifts and gel packs. Using specialized holders and an automated stage, the software-controlled microscope or macroscope can scan and map the sample in a few minutes.

Need for details or speed

If speed is needed, using the Clemex PSFilter with a macroscope will yield results for particles of 5 microns and up. If fine details are important, using a microscope will render particles of 0.5 microns and up.

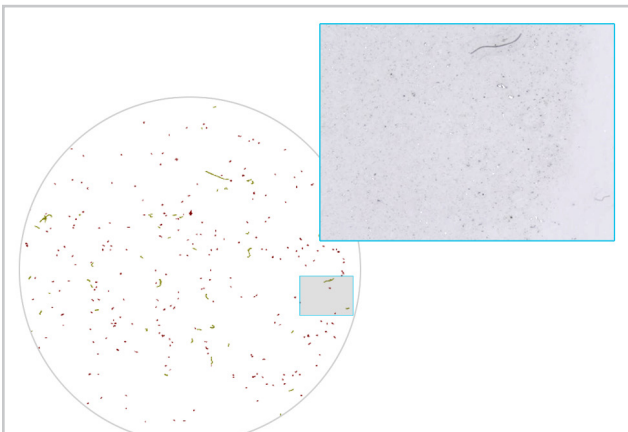
High precision solutions for cleanliness analysis

The measuring of particle contamination is of the utmost importance in the manufacturing and pharmaceutical industries. Damage caused by these particles can often have detrimental effects in machinery and harmful effects in pharmaceuticals. That is why the Clemex PSFilter is specially designed to analyse contamination in different areas by measuring particles collected on membrane filters, wafers, tape lifts, or gel packs.



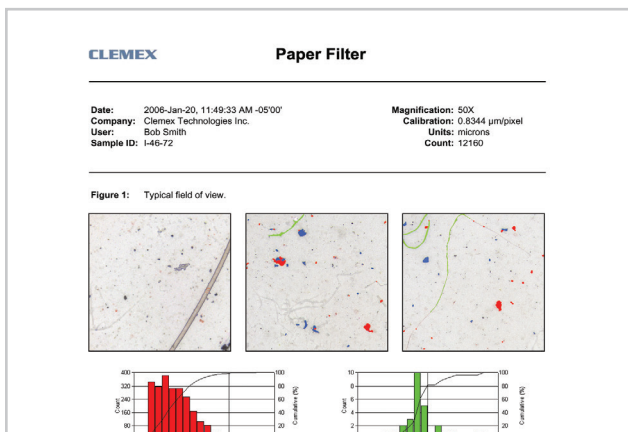
A single data sheet for large and small particles

Some samples contain a great range of particle sizes. Clemex PSFilter scans these types of samples twice, first at high magnification then at low magnification, and combines the results from both analyses into one data sheet.



All types of particles detected in one run

Clemex PSFilter automatically scans the sample and detects all particles of interest in a single step. As each field is analyzed, particles are measured and sorted based on their size, morphology or color. Data sheets are updated instantly.



Fast and reproducible results

The instrument processes a large number of images, classifies the particulates and generates an easily reproducible report in just a few minutes. These accurate measurement results can then be used for documentation and presentation purposes.

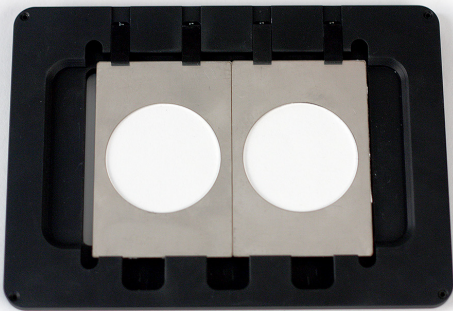
Particulate analysis in 3 easy steps

Place the sample on the holder, choose a method, click start and in a matter of seconds the results are tabulated. Everything is repeatable and traceable. Need to modify a run? The Clemex PSFilter comes with a complete list of modifiable parameters, allowing you to customize a run.



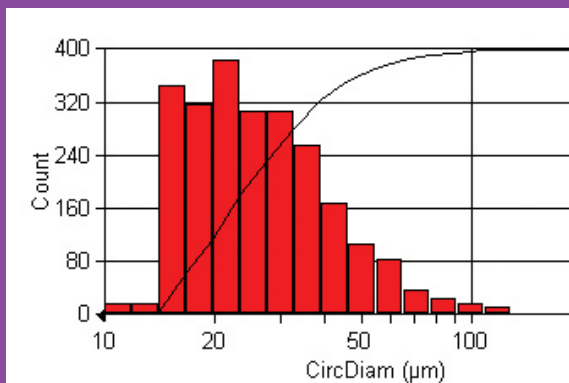
Step 1

Select your standard



Step 2

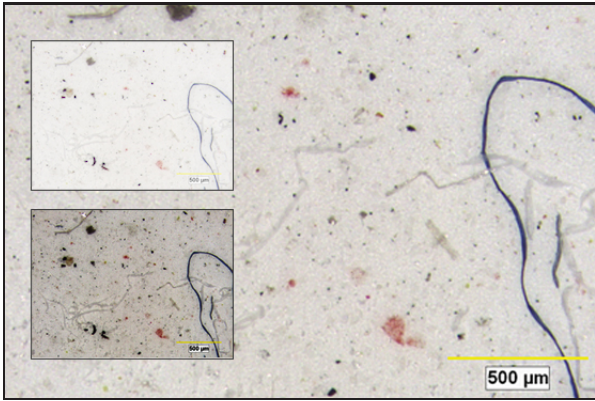
Scan your sample



Step 3

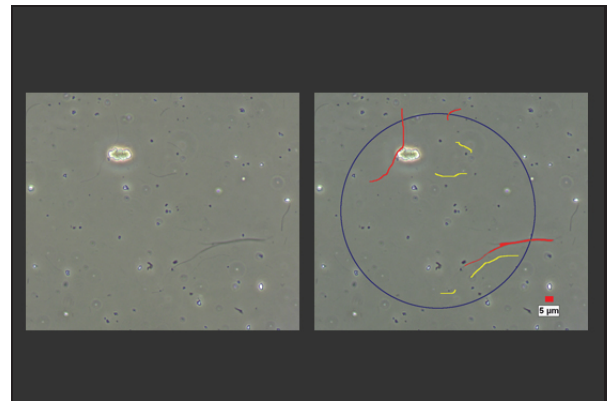
Export your results

Product Features



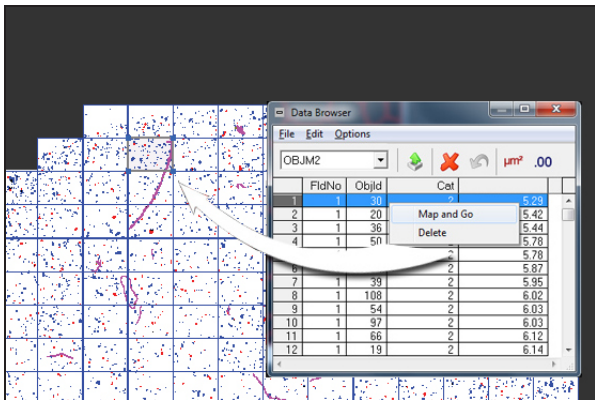
Auto Exposure

Once you have set the initial target intensity, you can duplicate lighting conditions any time with a simple click of the Auto Exposure button. Adjusting camera shutter speed manually is not necessary.



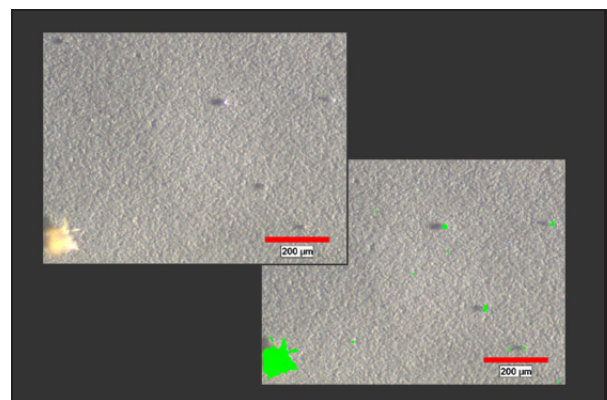
Contrast Threshold

Transparency, low contrast and more or less perceptible outlines make some objects hard to distinguish. Contrast Thresholding is ideal for faint objects on a filter, thin-walled cells and variable thickness crystals.



Object Tracking

Primarily a built-in spreadsheet, Clemex PFilter's Data Browser also remembers the positions of all analyzed objects, even in multiple-field environments. This allows you to validate detected objects, delete artifacts, and sort the final results.



Oblique illumination for USP 788

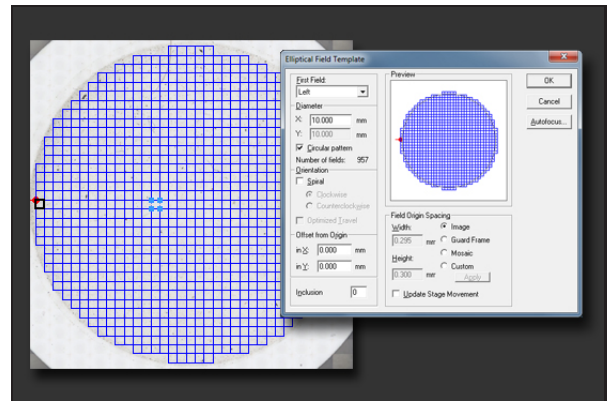
For transparent or translucent particulates on a membrane filter. In addition to internal reflected light, the instrument has an external auxiliary illuminator adjustable to give reflected oblique illumination at an angle of 10° to 20°.

Product Features



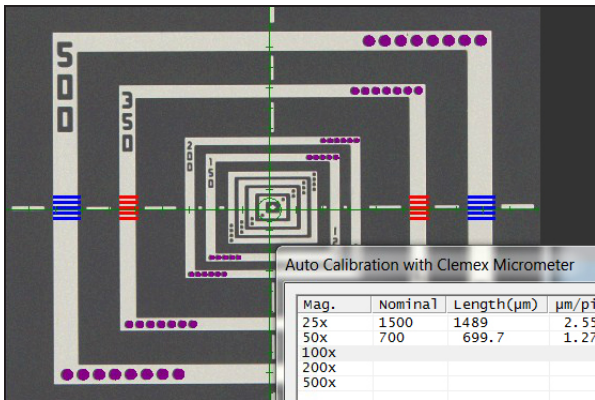
Camera and Microscope

Cameras and automated microscopes can be controlled directly within an imaging script. Automating this step means the following can be changed during analysis without any manual adjustments: 1. calibration / intensity | 2. magnification | 3. illumination / contrast



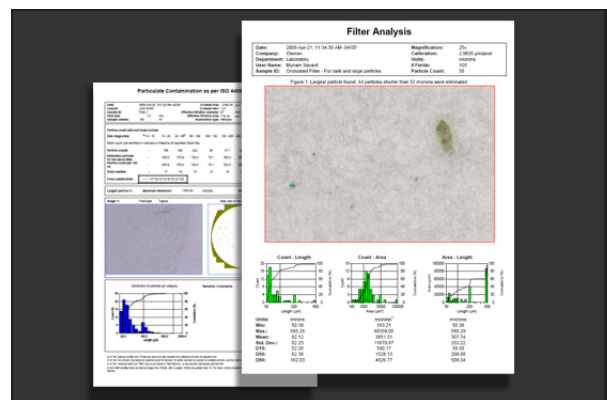
Circular Stage Pattern

This feature helps you to easily create rounded stage patterns when analyzing membrane filters or wafers. You control variables such as size, shape, and the number of fields while the software does the rest.



NIST-Traceable Auto Calibration

Using our NIST traceable micrometer, Clemex software automatically calibrates each lens, eliminating operator subjectivity. The system returns accurate, reproducible and traceable results.



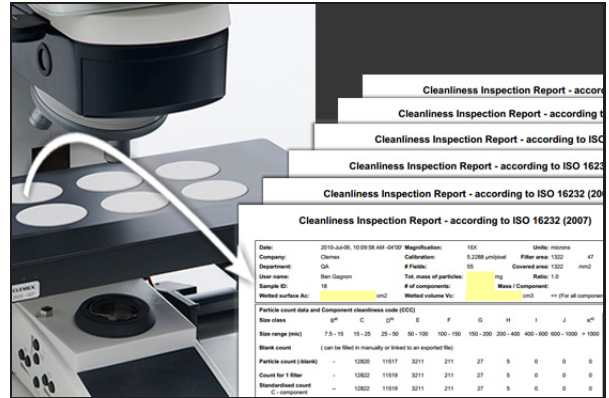
Professional-Looking Reports

Reports are generated automatically after each analysis and can be customized to suit your needs. You can add a company logo, images taken during analysis, graphs and charts, statistics and results.



+ As small as 0.5 microns

Clemex Microscope PSFilter. If the need for detail and accurate measurements is your most important consideration, this microscope-based instrument for measuring particulates right down to 0.5 μm should be your choice.



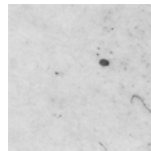
Multiple Sample Management

Depending on your scanning stage and filter holder, you may wish to analyze more than one sample in a single run. Our software handles up to six filter membranes. At the end of the analysis, each filter's raw data can be validated individually and separate reports are generated.

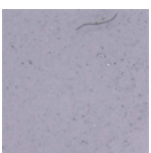
Related Web Reports



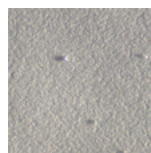
Cleanliness Evaluation



Cleanliness Inspection



Particulate contamination



Particulate count

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Metal Parts

Contaminants

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